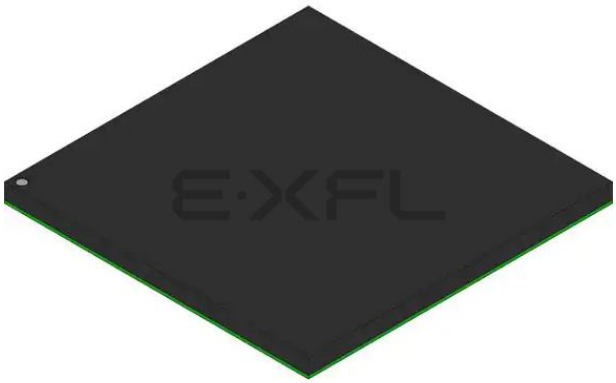
Altera - EP1SGX25DF672C5N Datasheet



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Understanding Embedded - FPGAs (Field Programmable Gate Array)

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Applications of Embedded - FPGAs

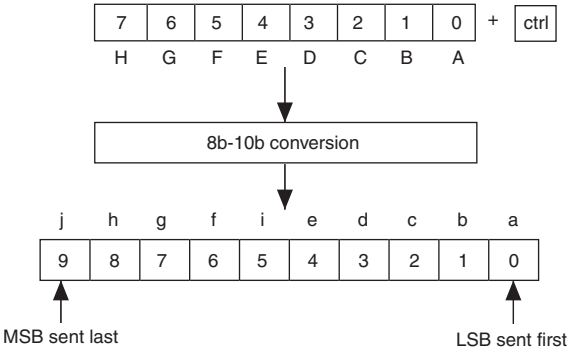
The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	455
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	672-BBGA, FCBGA
Supplier Device Package	672-FBGA (27x27)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=ep1sgx25df672c5n

8B/10B Encoder

The 8B/10B encoder translates 8-bit wide data + 1 control enable bit into a 10-bit encoded data. The encoded data has a maximum run length of 5. The 8B/10B encoder can be bypassed. Figure 2–4 diagrams the encoding process.

Figure 2–4. Encoding Process



Transmit State Machine

The transmit state machine operates in either XAUI mode or in GIGE mode, depending on the protocol used.

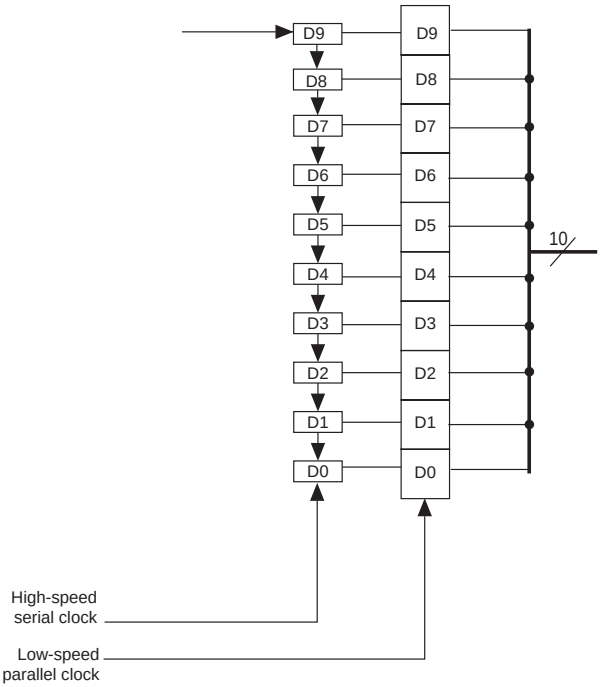
GIGE Mode

In GIGE mode, the transmit state machines convert all idle ordered sets (/K28.5/, /Dx.y/) to either /I1/ or /I2/ ordered sets. /I1/ consists of a negative-ending disparity /K28.5/ (denoted by /K28.5/-) followed by a neutral /D5.6/. /I2/ consists of a positive-ending disparity /K28.5/ (denoted by /K28.5/+) and a negative-ending disparity /D16.2/ (denoted by /D16.2/-). The transmit state machines do not convert any of the ordered sets to match /C1/ or /C2/, which are the configuration ordered sets. (/C1/ and /C2/ are defined by (/K28.5/, /D21.5/) and (/K28.5/, /D2.2/), respectively.) Both the /I1/ and /I2/ ordered sets guarantee a negative-ending disparity after each ordered set. The GIGE transmit state machine can be statically disabled in the Quartus II software, even if using the GIGE protocol mode.

Deserializer (Serial-to-Parallel Converter)

The deserializer converts the serial stream into a parallel 8- or 10-bit data bus. The deserializer receives the least significant bit first. Figure 2–14 is a diagram of the deserializer.

Figure 2–14. Deserializer



Word Aligner

The word aligner aligns the incoming data based on the specific byte boundaries. The word aligner has three customizable modes of operation: bit-slip mode, 16-bit mode, and 10-bit mode, the last of which is available for the basic and SONET modes. The word aligner also has two non-customizable modes of operation, which are the XAUI and GIGE modes.

Figure 2–15 shows the word aligner in bit-slip mode.

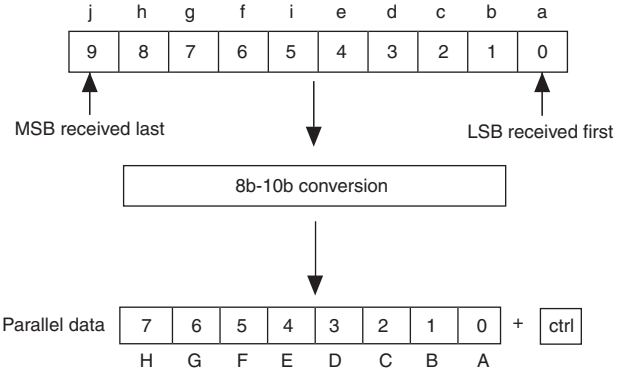
XAUI Mode

In XAUI mode, the rate matcher adheres to clause 48 of the IEEE 802.3ae specification for clock rate compensation. The rate matcher performs clock compensation on columns of /R/ (/K28.0/), denoted by //R//. An //R// is added or deleted automatically based on the number of words in the FIFO buffer.

8B/10B Decoder

The 8B/10B decoder converts the 10-bit encoded code group into 8-bit data and 1 control bit. The 8B/10B decoder can be bypassed. The following is a diagram of the conversion from a 10-bit encoded code group into 8-bit data + 1-bit control.

Figure 2–20. 8B/10B Decoder Conversion



There are two optional error status ports available in the 8B/10B decoder, rx_errdetect and rx_disperr. Table 2–7 shows the values of the ports from a given error. These status signals are aligned with the code group in which the error occurred.

Table 2–7. Error Signal Values

Types of Errors	rx_errdetect	rx_disperr
No errors	1'b0	1'b0
Invalid code groups	1'b1	1'b0
Disparity errors	1'b1	1'b1

Table 2–9. BIST Data Output & Verifier Alignment Pattern (Part 2 of 2)

BIST Mode	Output	Polynomials	Verifier Word Alignment Pattern
PRBS 16-bit	$2^8 - 1$	$x^8 + x^7 + x^5 + x^3 + 1$	1000000011111111
PRBS 20-bit	$2^{10} - 1$	$x^{10} + x^7 + 1$	1111111111
Incremental 10-bit	K28.5, K27.7, Data (00-FF incremental), K28.0, K28.1, K28.2, K28.3, K28.4, K28.6, K28.7, K23.7, K30.7, K29.7 *(1)*		0101111100 (K28.5)
Incremental 20-bit	K28.5, K27.7, Data (00-FF incremental), K28.0, K28.1, K28.2, K28.3, K28.4, K28.6, K28.7, K23.7, K30.7, K29.7 *(1)*		0101111100 (K28.5)
High frequency	1010101010		
Low frequency	0011111000		
Mixed frequency	0011111010 or 1100000101		

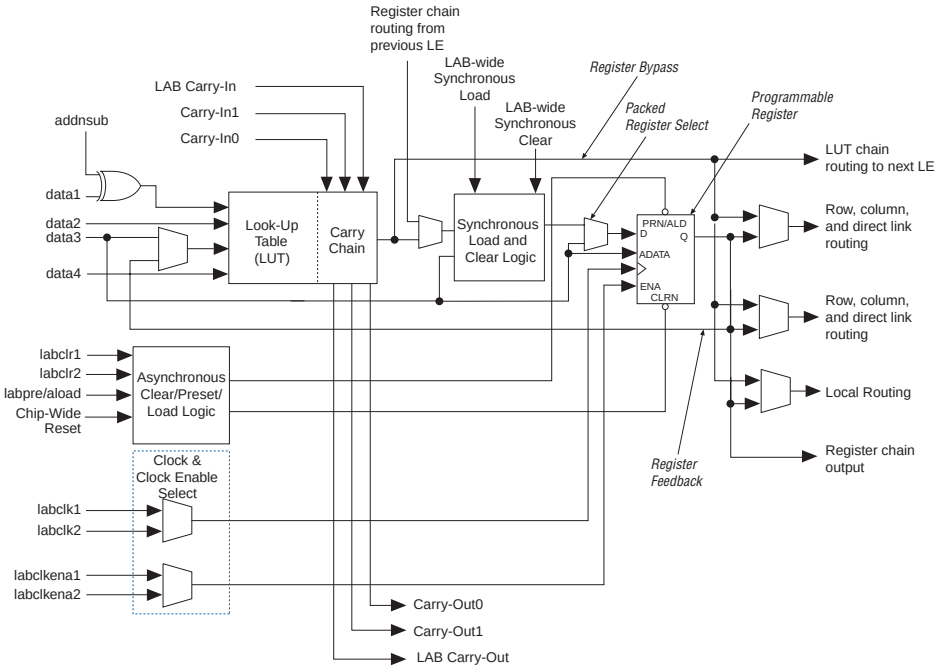
Note to Table 2–9:
(1) This output repeats.

Stratix GX Clocking

The Stratix GX global clock can be driven by certain REFCLKB pins, all transmitter PLL outputs, and all receiver PLL outputs. The REFCLKB pins (except for transceiver block 0 and transceiver block 4) can drive inter-transceiver and global clock lines as well as feed the transmitter and receiver PLLs. The output of the transmitter PLL can only feed global clock lines and the reference clock port of the receiver PLL.

Figures 2–26 and 2–27 are diagrams of the Inter-Transceiver line connections as well as the global clock connections for the EP1SGX25F and EP1SGX40G devices. For devices with fewer transceivers, ignore the information about the unavailable transceiver blocks.

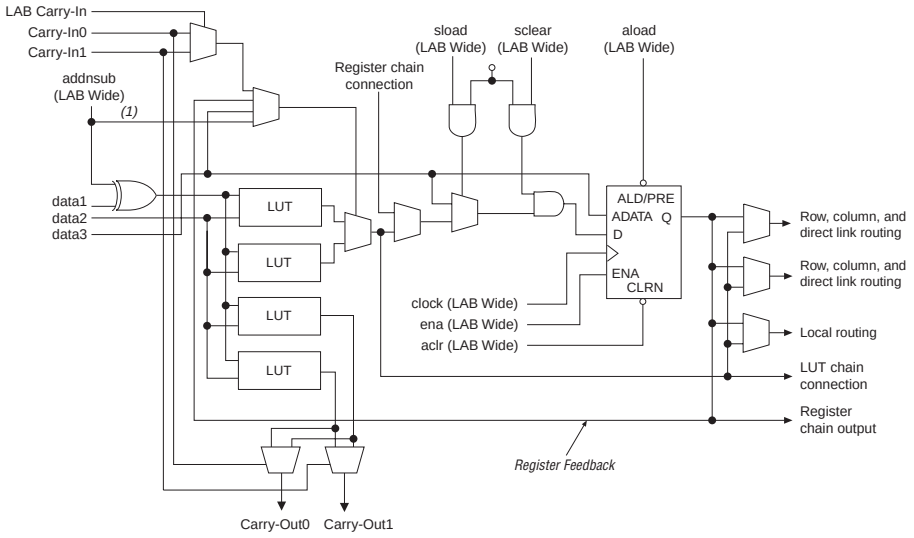
Figure 4–4. Stratix GX LE



Each LE's programmable register can be configured for D, T, JK, or SR operation. Each register has data, true asynchronous load data, clock, clock enable, clear, and asynchronous load/preset inputs. Global signals, general-purpose I/O pins, or any internal logic can drive the register's clock and clear control signals. Either general-purpose I/O pins or internal logic can drive the clock enable, preset, asynchronous load, and asynchronous data. The asynchronous load data input comes from the `data3` input of the LE. For combinatorial functions, the register is bypassed and the output of the LUT drives directly to the outputs of the LE.

Each LE has three outputs that drive the local, row, and column routing resources. The LUT or register output can drive these three outputs independently. Two LE outputs drive column or row and direct link routing connections and one drives local interconnect resources. This allows the LUT to drive one output while the register drives another output. This feature, called register packing, improves device utilization because the device can use the register and the LUT for unrelated functions. Another special packing mode allows the register output to feed back into the LUT of the same LE so that the register is packed with

Figure 4–6. LE in Dynamic Arithmetic Mode



Note to Figure 4–6:
(1) The addnsub signal is tied to the carry input for the first LE of a carry chain only.

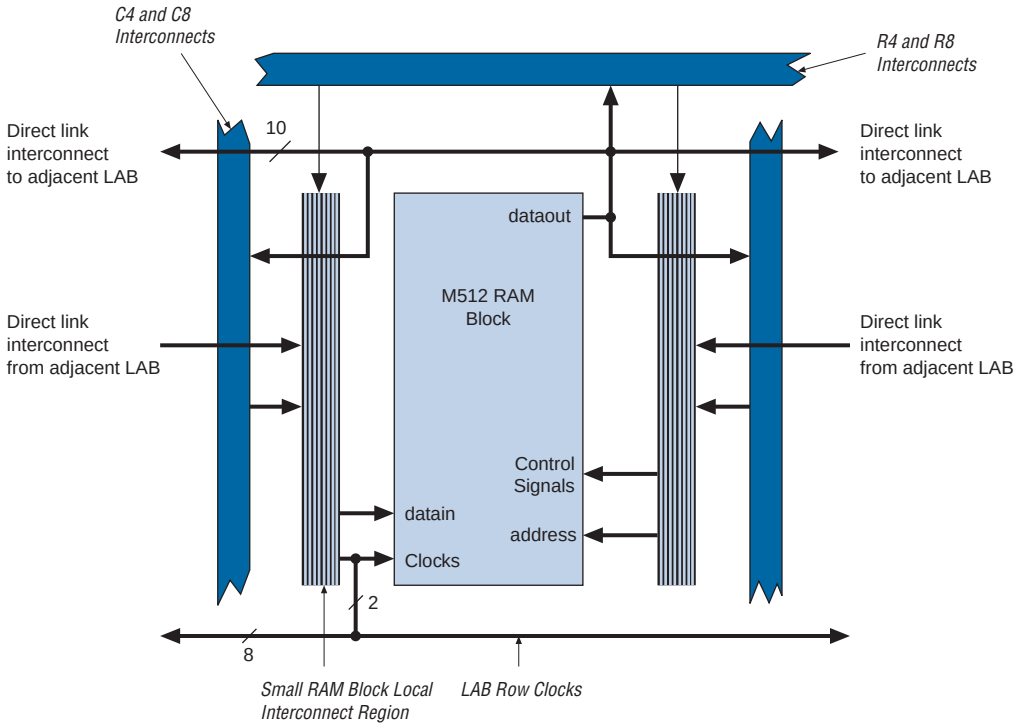
Carry-Select Chain

The carry-select chain provides a very fast carry-select function between LEs in arithmetic mode. The carry-select chain uses the redundant carry calculation to increase the speed of carry functions. The LE is configured to calculate outputs for a possible carry-in of 1 and carry-in of 0 in parallel. The carry-in0 and carry-in1 signals from a lower-order bit feed forward into the higher-order bit via the parallel carry chain and feed into both the LUT and the next portion of the carry chain. Carry-select chains can begin in any LE within an LAB.

The speed advantage of the carry-select chain is in the parallel pre-computation of carry chains. Because the LAB carry-in selects the precomputed carry chain, not every LE is in the critical path. Only the propagation delay between LAB carry-in generation (LE 5 and LE 10) are now part of the critical path. This feature allows the Stratix GX architecture to implement high-speed counters, adders, multipliers, parity functions, and comparators of arbitrary width.

Figure 4–7 shows the carry-select circuitry in an LAB for a 10-bit full adder. One portion of the LUT generates the sum of two bits using the input signals and the appropriate carry-in bit; the sum is routed to the output of the LE. The register can be bypassed for simple adders or used

Figure 4–15. M512 RAM Block LAB Row Interface



M4K RAM Blocks

The M4K RAM block includes support for true dual-port RAM. The M4K RAM block implements buffers for a wide variety of applications such as storing processor code, implementing lookup schemes, and implementing larger memory applications. Each block contains 4,608 RAM bits (including parity bits). M4K RAM blocks can be configured in the following modes:

- True dual-port RAM
- Simple dual-port RAM
- Single-port RAM
- FIFO
- ROM
- Shift register

When configured as RAM or ROM, you can use an initialization file to pre-load the memory contents.

Figure 4–16. M4K RAM Block Control Signals

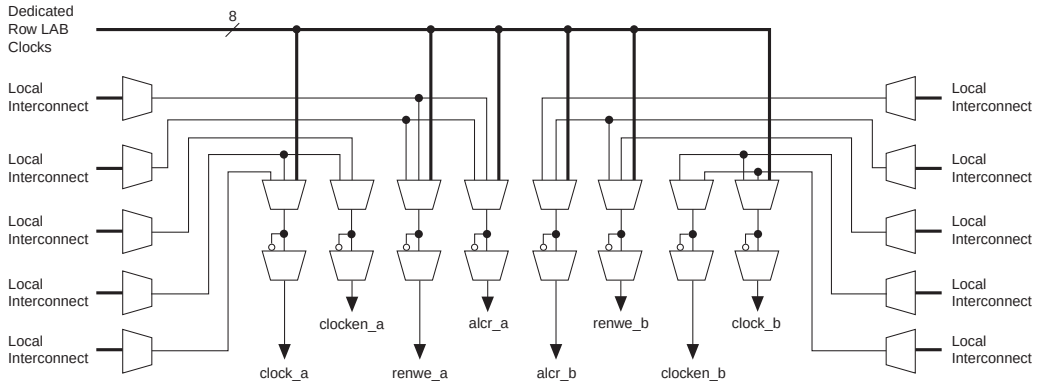
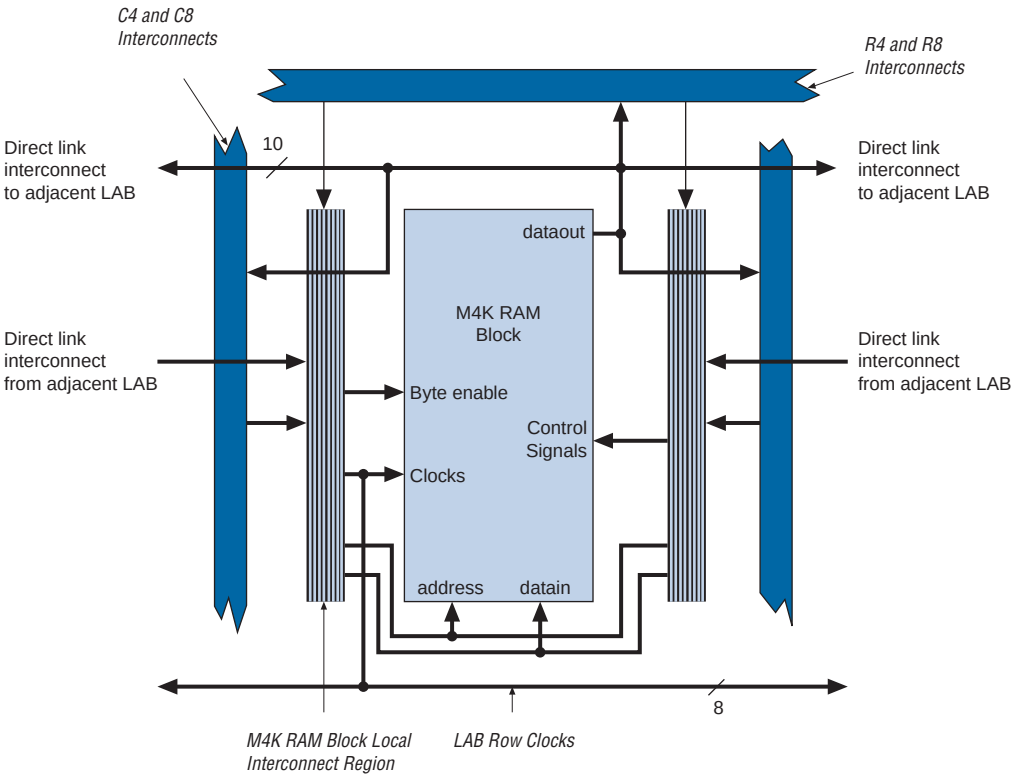


Figure 4–17. M4K RAM Block LAB Row Interface



M-RAM Block

The largest TriMatrix memory block, the M-RAM block, is useful for applications where a large volume of data must be stored on-chip. Each block contains 589,824 RAM bits (including parity bits). The M-RAM block can be configured in the following modes:

- True dual-port RAM
- Simple dual-port RAM
- Single-port RAM
- FIFO RAM

You cannot use an initialization file to initialize the contents of a M-RAM block. All M-RAM block contents power up to an undefined value. Only synchronous operation is supported in the M-RAM block, so all inputs are registered. Output registers can be bypassed. The memory address and output width can be configured as 64K × 8 (or 64K × 9 bits), 32K × 16 (or 32K × 18 bits), 16K × 32 (or 16K × 36 bits), 8K × 64 (or 8K × 72 bits), and 4K × 128 (or 4K × 144 bits). The 4K × 128 configuration is unavailable in true dual-port mode because there are a total of 144 data output drivers in the block. Mixed-width configurations are also possible, allowing different read and write widths. Tables 4–7 and 4–8 summarize the possible M-RAM block configurations:

Table 4–7. M-RAM Block Configurations (Simple Dual-Port)

Read Port	Write Port				
	64K × 9	32K × 18	16K × 36	8K × 72	4K × 144
64K × 9	✓	✓	✓	✓	
32K × 18	✓	✓	✓	✓	
16K × 36	✓	✓	✓	✓	
8K × 72	✓	✓	✓	✓	
4K × 144					✓

Table 4–10. M-RAM Combined Byte Selection for ×144 Mode Notes (1), (2)	
byteena[15..0]	**datain ×144**
[0] = 1	[8..0]
[1] = 1	[17..9]
[2] = 1	[26..18]
[3] = 1	[35..27]
[4] = 1	[44..36]
[5] = 1	[53..45]
[6] = 1	[62..54]
[7] = 1	[71..63]
[8] = 1	[80..72]
[9] = 1	[89..81]
[10] = 1	[98..90]
[11] = 1	[107..99]
[12] = 1	[116..108]
[13] = 1	[125..117]
[14] = 1	[134..126]
[15] = 1	[143..135]

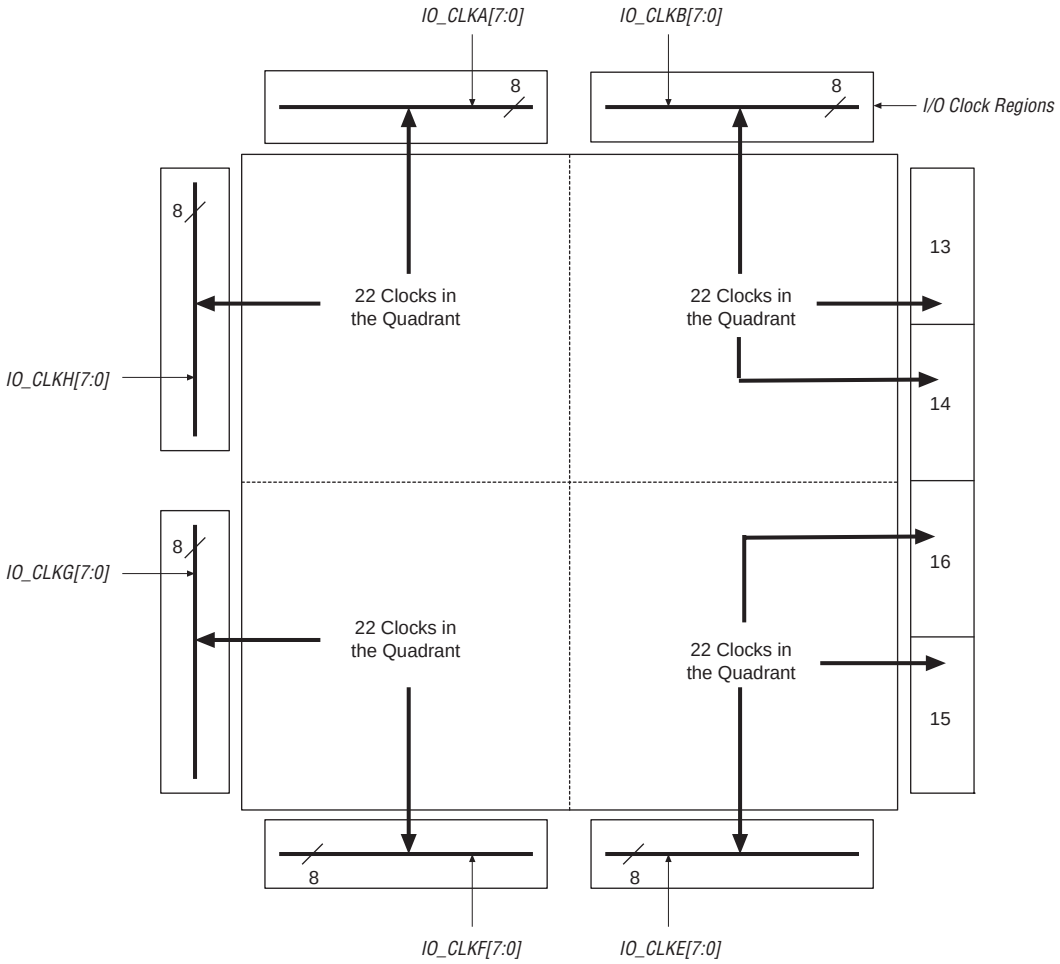
Notes to Tables 4–9 and 4–10:

(1) Any combination of byte enables is possible.

(2) Byte enables can be used in the same manner with 8-bit words, that is, in ×16, ×32, ×64, and ×128 modes.

Similar to all RAM blocks, M-RAM blocks can have different clocks on their inputs and outputs. All input registers—`renwe`, `datain`, address, and byte enable registers—are clocked together from either of the two clocks feeding the block. The output register can be bypassed. The eight `labclk` signals or local interconnect can drive the control signals for the A and B ports of the M-RAM block. LEs can also control the `clock_a`, `clock_b`, `renwe_a`, `renwe_b`, `clr_a`, `clr_b`, `clocken_a`, and `clocken_b` signals as shown in Figure 4–18.

Figure 4–46. EP1SGX25 & EP1SGX10 Device I/O Clock Groups



The areset signals are reset/resynchronization inputs for each PLL. The areset signal should be asserted every time the PLL loses lock to guarantee correct phase relationship between the PLL output clocks. Users should include the areset signal in designs if any of the following conditions are true:

- PLL Reconfiguration or Clock switchover enables in the design.
- Phase relationships between output clocks need to be maintained after a loss of lock condition

The device input pins or logic elements (LEs) can drive these input signals. When driven high, the PLL counters resets, clearing the PLL output and placing the PLL out of lock. The VCO sets back to its nominal setting (~700 MHz). When driven low again, the PLL resynchronizes to its input as it relocks. If the target VCO frequency is below this nominal frequency, then the output frequency starts at a higher value than desired as the PLL locks. If the system cannot tolerate this, the clkena signal can disable the output clocks until the PLL locks.

The pfdena signals control the phase frequency detector (PFD) output with a programmable gate. If you disable the PFD, the VCO operates at its last set value of control voltage and frequency with some long-term drift to a lower frequency. The system continues running when the PLL goes out of lock or the input clock is disabled. By maintaining the last locked frequency, the system has time to store its current settings before shutting down. You can either use your own control signal or a clkloss status signal to trigger pfdena.

The clkena signals control the enhanced PLL regional and global outputs. Each regional and global output port has its own clkena signal. The clkena signals synchronously disable or enable the clock at the PLL output port by gating the outputs of the *g* and *l* counters. The clkena signals are registered on the falling edge of the counter output clock to enable or disable the clock without glitches. Figure 4–56 shows the waveform example for a PLL clock port enable. The PLL can remain locked independent of the clkena signals since the loop-related counters are not affected. This feature is useful for applications that require a low power or sleep mode. Upon re-enabling, the PLL does not need a resynchronization or relock period. The clkena signal can also disable clock outputs if the system is not tolerant to frequency overshoot during resynchronization.

The extclkena signals work in the same way as the clkena signals, but they control the external clock output counters (*e*0, *e*1, *e*2, and *e*3). Upon re-enabling, the PLL does not need a resynchronization or relock period

Programmable delays can increase the register-to-pin delays for output and/or output enable registers. A programmable delay exists to increase the t_{ZX} delay to the output pin, which is required for ZBT interfaces. Table 4–21 shows the programmable delays for Stratix GX devices.

Table 4–21. Stratix GX Programmable Delay Chain

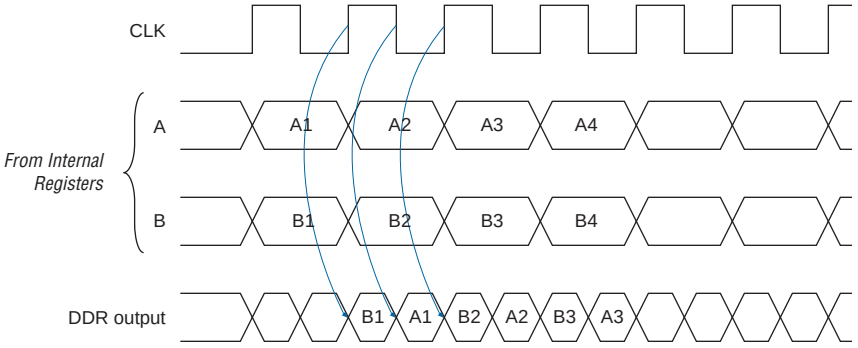
Programmable Delays	Quartus II Logic Option
Input pin to logic array delay	Decrease input delay to internal cells
Input pin to input register delay	Decrease input delay to input register
Output pin delay	Increase delay to output pin
Output enable register t_{CO} delay	Increase delay to output enable pin
Output t_{ZX} delay	Increase t_{ZX} delay to output pin
Output clock enable delay	Increase output clock enable delay
Input clock enable delay	Increase input clock enable delay
Logic array to output register delay	Decrease input delay to output register
Output enable clock enable delay	Increase output enable clock enable delay

The IOE registers in Stratix GX devices share the same source for clear or preset. You can program preset or clear for each individual IOE. You can also program the registers to power up high or low after configuration is complete. If programmed to power up low, an asynchronous clear can control the registers. If programmed to power up high, an asynchronous preset can control the registers. This feature prevents the inadvertent activation of another device's active-low input upon power-up. If one register in an IOE uses a preset or clear signal then all registers in the IOE must use that same signal if they require preset or clear. Additionally, a synchronous reset signal is available for the IOE registers.

Double-Data Rate I/O Pins

Stratix GX devices have six registers in the IOE, which support DDR interfacing by clocking data on both positive and negative clock edges. The IOEs in Stratix GX devices support DDR inputs, DDR outputs, and bidirectional DDR modes.

Figure 4–67. Output Timing Diagram in DDR Mode



The Stratix GX IOE operates in bidirectional DDR mode by combining the DDR input and DDR output configurations. Stratix GX device I/O pins transfer data on a DDR bidirectional bus to support DDR SDRAM. The negative-edge-clocked OE register holds the OE signal inactive until the falling edge of the clock. This is done to meet DDR SDRAM timing requirements.

External RAM Interfacing

Stratix GX devices support DDR SDRAM at up to 200 MHz (400-Mbps data rate) through dedicated phase-shift circuitry, QDR and QDRII SRAM interfaces up to 167 MHz, and ZBT SRAM interfaces up to 200 MHz. Stratix GX devices also provide preliminary support for reduced latency DRAM II (RLDRAM II) at rates up to 200 MHz through the dedicated phase-shift circuitry.

In addition to the required signals for external memory interfacing, Stratix GX devices offer the optional clock enable signal. By default the Quartus II software sets the clock enable signal high, which tells the output register to update with new values. The output registers hold their own values if the design sets the clock enable signal low. See Figure 4–63.

To find out more about the DDR SDRAM specification, see the JEDEC web site (**www.jedec.org**). For information on memory controller megafunctions for Stratix GX devices, see the Altera web site (**www.altera.com**). See *AN 342: Interfacing DDR SDRAM with Stratix & Stratix GX Devices* for more information on DDR SDRAM interface in Stratix GX. Also see *AN 349: QDR SRAM Controller Reference Design for Stratix & Stratix GX Devices* and *AN 329: ZBT SRAM Controller Reference Design for Stratix & Stratix GX Devices*.

Table 6–2. Stratix GX Device Recommended Operating Conditions (Part 2 of 2) *Note (7), (12), (13)*

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_O	Output voltage		0	V_{CCIO}	V
T_J	Operating junction temperature	For commercial use	0	85	° C
		For industrial use	–40	100	° C

Table 6–3. Stratix GX Device DC Operating Conditions *Note (12)*

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
I_I	Input pin leakage current	$V_I = V_{CCIOmax}$ to 0 V *(8)*	–10		10	µA
I_{OZ}	Tri-stated I/O pin leakage current	$V_O = V_{CCIOmax}$ to 0 V *(8)*	–10		10	µA
R_{CONF}	Value of I/O pin pull-up resistor before and during configuration	V_{CCIO} = 3.0 V *(9)*	20		50	kΩ
		V_{CCIO} = 2.375 V *(9)*	30		80	kΩ
		V_{CCIO} = 1.71 V *(9)*	60		150	kΩ

Table 6–4. Stratix GX Transceiver Block Absolute Maximum Ratings

Symbol	Parameter	Conditions	Minimum	Maximum	Units
V_{CCA}	Transceiver block supply voltage	Commercial and industrial	–0.5	4.6	V
V_{CCP}	Transceiver block supply voltage	Commercial and industrial	–0.5	2.4	V
V_{CCR}	Transceiver block supply Voltage	Commercial and industrial	–0.5	2.4	V
V_{CCT}	Transceiver block supply voltage	Commercial and industrial	–0.5	2.4	V
V_{CCG}	Transceiver block supply voltage	Commercial and industrial	–0.5	2.4	V
Receiver input voltage	V_{ICM} ±V_{ID} single / 2	Commercial and industrial		1.675 *(10)*, *(13)*	V
`refclkb` input voltage	V_{ICM} ±V_{ID} single / 2	Commercial and industrial		1.675 *(10)*, *(13)*	V

Table 6–29. 1.5-V HSTL Class I Specifications (Part 2 of 2)

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Units
V_{OH}	High-level output voltage	I_{OH} = 8 mA *(1)*	V_{CCIO} – 0.4			V
V_{OL}	Low-level output voltage	I_{OH} = –8 mA *(1)*			0.4	V

Table 6–30. 1.5-V HSTL Class II Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Units
V_{CCIO}	Output supply voltage		1.4	1.5	1.6	V
V_{REF}	Input reference voltage		0.68	0.75	0.9	V
V_{TT}	Termination voltage		0.7	0.75	0.8	V
V_{IH} (DC)	DC high-level input voltage		V_{REF} + 0.1			V
V_{IL} (DC)	DC low-level input voltage		–0.3		V_{REF} – 0.1	V
V_{IH} (AC)	AC high-level input voltage		V_{REF} + 0.2			V
V_{IL} (AC)	AC low-level input voltage				V_{REF} – 0.2	V
V_{OH}	High-level output voltage	I_{OH} = 16 mA *(1)*	V_{CCIO} – 0.4			V
V_{OL}	Low-level output voltage	I_{OH} = –16 mA *(1)*			0.4	V

Table 6–31. 1.5-V Differential HSTL Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Units
V_{CCIO}	I/O supply voltage		1.4	1.5	1.6	V
V_{DIF} (DC)	DC input differential voltage		0.2			V
V_{CM} (DC)	DC common mode input voltage		0.68		0.9	V
V_{DIF} (AC)	AC differential input voltage		0.4			V

Table 6–32. CTT I/O Specifications (Part 1 of 2)

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Units
V_{CCIO}	Output supply voltage		3.0	3.3	3.6	V
V_{TT}/V_{REF}	Termination and input reference voltage		1.35	1.5	1.65	V
V_{IH}	High-level input voltage		V_{REF} + 0.2			V
V_{IL}	Low-level input voltage				V_{REF} – 0.2	V

Preliminary & Final Timing

Timing models can have either preliminary or final status. The Quartus® II software displays an informational message during the design compilation if the timing models are preliminary. Table 6–34 shows the status of the Stratix GX device timing models.

Preliminary status means the timing model is subject to change. Initially, timing numbers are created using simulation results, process data, and other known parameters. These tests are used to make the preliminary numbers as close to the actual timing parameters as possible.

Final timing numbers are based on actual device operation and testing. These numbers reflect the actual performance of the device under worst-case voltage and junction temperature conditions.

Table 6–34. Stratix GX Device Timing Model Status

Device	Preliminary	Final
EP1SGX10	—	✓
EP1SGX25	—	✓
EP1SGX40	—	✓

Performance

Table 6–35 shows Stratix GX device performance for some common designs. All performance values were obtained with Quartus II software compilation of LPM, or MegaCore® functions for the FIR and FFT designs.

Table 6–35. Stratix GX Device Performance (Part 1 of 3) *Notes (1), (2)*

Applications		Resources Used			Performance			
		LEs	TriMatrix Memory Blocks	DSP Blocks	-5 Speed Grade	-6 Speed Grade	-7 Speed Grade	Units
LE	16-to-1 multiplexer *(1)*	22	0	0	407.83	324.56	288.68	MHz
	32-to-1 multiplexer *(3)*	46	0	0	318.26	255.29	242.89	MHz
	16-bit counter	16	0	0	422.11	422.11	390.01	MHz
	64-bit counter	64	0	0	321.85	290.52	261.23	MHz

Table 6–59. EP1SGX10 Row Pin Global Clock External I/O Timing Parameters (Part 2 of 2)

Symbol	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
t_{OUTCO}	2.000	5.231	2.000	5.293	2.000	5.822	ns
$t_{INSUPLL}$	1.126		1.186		1.352		ns
t_{INHPLL}	0.000		0.000		0.000		ns
$t_{OUTCOPLL}$	0.500	2.804	0.500	2.627	0.500	2.765	ns

Tables 6–60 through 6–65 show the external timing parameters on column and row pins for EP1SGX25 devices.

Table 6–60. EP1SGX25 Column Pin Fast Regional Clock External I/O Timing Parameters

Symbol	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
t_{INSU}	2.418		2.618		3.014		ns
t_{INH}	0.000		0.000		0.000		ns
t_{OUTCO}	2.000	4.524	2.000	4.834	2.000	5.538	ns

Table 6–61. EP1SGX25 Column Pin Regional Clock External I/O Timing Parameters

Symbol	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
t_{INSU}	1.713		1.838		2.069		ns
t_{INH}	0.000		0.000		0.000		ns
t_{OUTCO}	2.000	5.229	2.000	5.614	2.000	6.432	ns
$t_{INSUPLL}$	1.061		1.155		1.284		ns
t_{INHPLL}	0.000		0.000		0.000		ns
$t_{OUTCOPLL}$	0.500	2.661	0.500	2.799	0.500	3.195	ns

Table 6–71. EP1SGX40 Row Pin Global Clock External I/O Timing Parameters (Part 2 of 2)

Symbol	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
t_{OUTCO}	2.000	5.365	2.000	5.775	2.000	6.621	ns
$t_{INSUPLL}$	1.126		1.186		1.352		ns
t_{INHPLL}	0.000		0.000		0.000		ns
$t_{OUTCOPLL}$	0.500	2.304	0.500	2.427	0.500	2.765	ns

External I/O Delay Parameters

External I/O delay timing parameters, both for I/O standard input and output adders and programmable input and output delays, are specified by speed grade, independent of device density.

Tables 6–72 through 6–77 show the adder delays associated with column and row I/O pins. If an I/O standard is selected other than LVTTL 24 mA with a fast slew rate, add the selected delay to the external t_{CO} and t_{SU} I/O parameters.

Table 6–72. Stratix GX I/O Standard Column Pin Input Delay Adders (Part 1 of 2)

I/O Standard	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
LVCMOS		0		0		0	ps
3.3-V LVTTL		0		0		0	ps
2.5-V LVTTL		30		31		35	ps
1.8-V LVTTL		150		157		180	ps
1.5-V LVTTL		210		220		252	ps
GTL		220		231		265	ps
GTL+		220		231		265	ps
3.3-V PCI		0		0		0	ps
3.3-V PCI-X 1.0		0		0		0	ps
Compact PCI		0		0		0	ps
AGP 1×		0		0		0	ps
AGP 2×		0		0		0	ps
CTT		120		126		144	ps
SSTL-3 class I		–30		–32		–37	ps
SSTL-3 class II		–30		–32		–37	ps

Table 6–84. Stratix GX Maximum Output Clock Rate for PLL[5, 6, 11, 12] Pins (Part 2 of 2)

I/O Standard	-5 Speed Grade	-6 Speed Grade	-7 Speed Grade	Unit
1.8 V	250	250	250	MHz
1.5 V	225	200	200	MHz
LVCMOS	350	300	250	MHz
GTL	200	167	125	MHz
GTL+	200	167	125	MHz
SSTL-3 class I	167	150	133	MHz
SSTL-3 class II	167	150	133	MHz
SSTL-2 class I	200	200	167	MHz
SSTL-2 class II	200	200	167	MHz
SSTL-18 class I	150	133	133	MHz
SSTL-18 class II	150	133	133	MHz
1.5-V HSTL class I	250	225	200	MHz
1.5-V HSTL class II	225	200	200	MHz
1.8-V HSTL class I	250	225	200	MHz
1.8-V HSTL class II	225	200	200	MHz
3.3-V PCI	350	300	250	MHz
3.3-V PCI-X 1.0	350	300	250	MHz
Compact PCI	350	300	250	MHz
AGP 1×	350	300	250	MHz
AGP 2×	350	300	250	MHz
CTT	200	200	200	MHz
Differential HSTL	225	200	200	MHz
Differential SSTL-2	200	200	167	MHz
LVDS	500	500	500	MHz
LVPECL	500	500	500	MHz
PCML	350	350	350	MHz
HyperTransport technology	350	350	350	MHz

Table 6–85. Stratix GX Maximum Output Clock Rate (Using I/O Pins) for PLL[1, 2] Pins (Part 1 of 2)

I/O Standard	-5 Speed Grade	-6 Speed Grade	-7 Speed Grade	Unit
LVTTL	400	350	300	MHz
2.5 V	400	350	300	MHz
1.8 V	400	350	300	MHz